

<b>Notice of References Cited</b>	Application/Control No. 10/042,080	Applicant(s)/Patent Under Reexamination BERRY ET AL.	
	Examiner John P Trimmings	Art Unit 2133	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,195,776	02-2001	Ruiz et al.	714/738
	C	US-5,150,366	09-1992	Bardell et al.	714/728
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Scan Latch Design for Delay Test", Jacob Savir, 1997 Test Conference (IEEE Proceedings International), Nov 1-6 1997, pp 446-453.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.